Maximum Ratings

(Above which the useful life may be impaired. For user guidelines, not tested.)

Storage Temperature .....–65°C to +150°C

Ambient Temperature with Power Applied.....–55°C to +125°C

Supply Voltage to Ground Potential[1].....–0.5V to +7.0V

DC Voltage Applied to Outputs in High Z State[1] .....–0.5V to +7.0V

DC Input Voltage[1].....–0.5V to +7.0V

Output Current into Outputs (LOW)..... 20 mA

Static Discharge Voltage ..... >2001V (per MIL-STD-883, Method 3015.2)

Latch-Up Current..... >200 mA

Operating Range

Range	Ambient Temperature	V_{CC}
Commercial	0°C to + 70°C	5V ± 10%

Electrical Characteristics Over the Operating Range

Parameter	Description	Test Conditions	7C182-25, 35, 45		Unit
			Min.	Max.	
V_{OH}	Output HIGH Voltage	V_{CC} Min., I_{OH} = –4.0 mA.	2.4		V
V_{OL}	Output LOW Voltage	V_{CC} Min., I_{OL} = 8.0 mA		0.4	V
V_{IH}	Input HIGH Voltage		2.2	V_{CC}	V
V_{IL}	Input LOW Voltage[1]		–0.5	0.8	V
I_{IX}	Input Load Current	$GND \le V_{IN} \le V_{CC}$, $GND < V_{OUT} < V_{CC}$, Output Disabled	–10	+10	µA
I_{OZ}	Output Leakage Current	V_{CC} = Max., V_{OUT} = GND	–10	+10	µA
I_{OS}	Output Short Circuit Current[2]	V_{CC} = Max., V_{OUT} = GND		–300	mA
I_{CC}	V_{CC} Operating Circuit Current	V_{CC} Max., Output Current = 0 mA, f = Max., $V_{IN} = V_{CC}$ or GND		140	mA
	Automatic Power-Down Current — TTL Inputs	Max V_{CC}, $\overline{CE}_1 \ge V_{IH}$, $CE_2 \le V_{IL}$, $V_{IN} \ge V_{IH}$ or $V_{IN} \le V_{IL}$, f = f_{MAX}		35	mA
	Automatic Power-Down Current — CMOS Inputs	Max V_{CC}, $\overline{CE}_1 \ge V_{CC} - 0.3V$, $CE_2 \le 0.3V$, $V_{IN} \ge V_{CC} - 0.3V$ or $V_{IN} \le 0.3V$, f = 0		20	mA

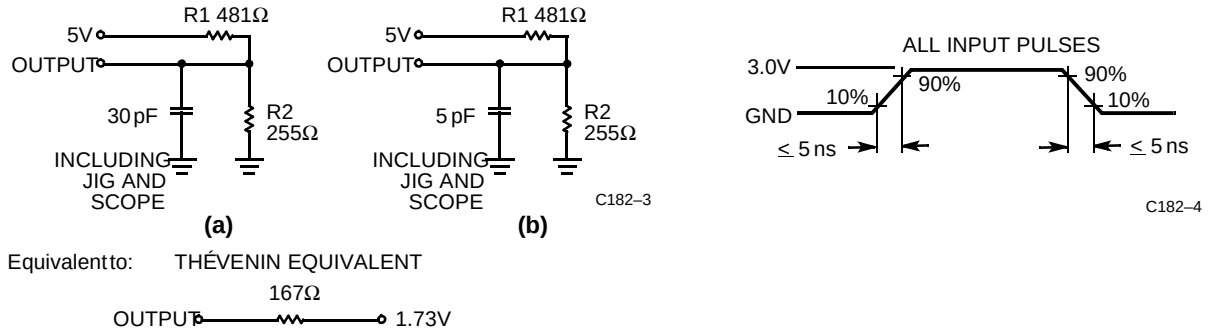
Capacitance[3]

Parameter	Description	Test Conditions	Max.	Unit
C_{OUT}	Output Capacitance	T_A = 25°C, f = 1 MHz, V_{CC} = 5.0V	10	pF
C_{IN}	Input Capacitance		10	pF

Note:

1. V_{IL} (min.) = –3.0V for pulse durations of less than 20 ns.
2. Duration of the short circuit should not exceed 30 seconds. Not more than one output should be shorted at one time.
3. Tested initially and after any design or process changes that may affect these parameters.

AC Test Loads and Waveforms



Switching Characteristics Over the Operating Range

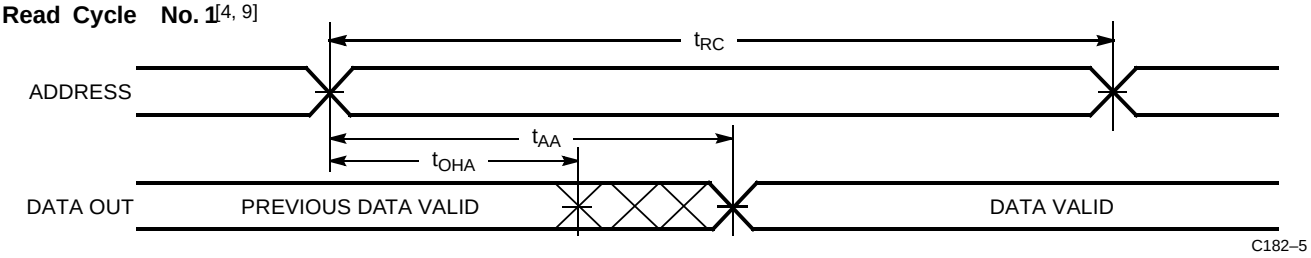
Parameter	Description	7C182-25		7C182-35		7C182-45		Unit
		Min.	Max.	Min.	Max.	Min.	Max.	
READ CYCLE[4]								
t_{RC}	Read Cycle Time	25		35		45		ns
t_{AA}	Address to Data Valid		25		35		45	ns
t_{OHA}	Data Hold from Address Change	3		3		3		ns
t_{ACE1}	$\overline{CE}_1$ Access Time		25		35		45	ns
t_{ACE2}	CE_2 Access Time		25		35		45	ns
t_{LZCE1}	$\overline{CE}_1$ LOW to Low Z	5		5		5		ns
t_{LZCE2}	CE_2 HIGH to Low Z	5		5		5		ns
t_{HZCE1}	$\overline{CE}_1$ HIGH to High Z[5]		18		20		25	ns
t_{HZCE2}	CE_2 LOW to High Z[5]		18		20		25	
t_{PU}	$\overline{CE}_1$ LOW to Power-Up	0		0		0		ns
t_{PD}	$\overline{CE}_1$ HIGH to Power-Down		20		20		25	ns
t_{DOE}	$\overline{OE}$ Access Time		18		20		20	ns
t_{LZOE}	$\overline{OE}$ LOW to Low Z	3		3		3		ns
t_{HZOE}	$\overline{OE}$ HIGH to High Z[5]		18		20		25	ns
WRITE CYCLE[6]								
t_{WC}	Write Cycle Time	25		35		45		ns
t_{SA}	Address Set-Up Time	0		0		0		ns
t_{AW}	Address Valid to End of Write	20		30		40		ns
t_{SD}	Data Set-Up Time	15		20		25		ns
t_{SCE1}	$\overline{CE}_1$ LOW to Write End	20		30		40		ns
t_{SCE2}	CE_2 HIGH to Write End	20		30		40		ns
t_{PWE}	$\overline{WE}$ Pulse Width	20		25		30		ns
t_{HA}	Address Hold from End of Write	0		0		0		ns
t_{HD}	Data Hold Time	0		0		0		ns
t_{LZWE}	Write HIGH to Low Z[7]	3		3		3		ns
t_{HZWE}	Write LOW to High Z[5, 7, 8]		13		15		20	ns

Notes:

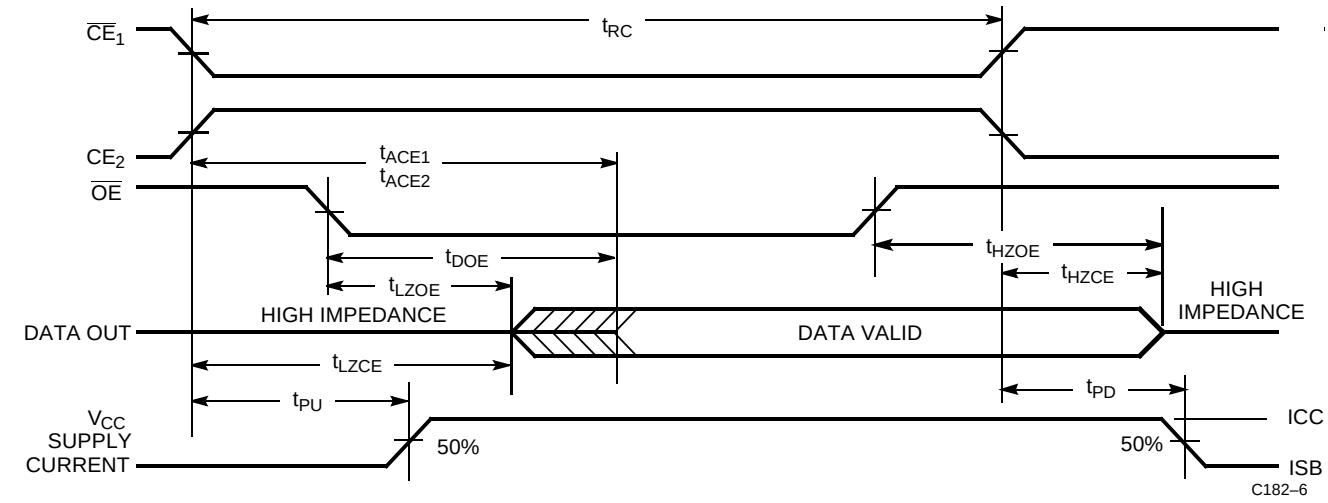
4. $\overline{WE}$ is HIGH for read cycle.
5. t_{HZCE} and t_{HZWE} are specified with C_L = 5 pF. Transition is measured ± 500 mV from steady-state voltage.
6. The internal write time of the memory is defined by the overlap of $\overline{CE}_1$ LOW, CE_2 HIGH, and $\overline{WE}$ LOW. All three signals must be asserted to initiate a write and any signal can terminate a write by being deasserted. The data input set-up and hold timing should be referenced to the rising edge of the signal that terminates the write.
7. At any given temperature and voltage condition, t_{LZWE} is less than t_{HZWE} for any given device. These parameters are sampled and not 100% tested.
8. Address valid prior to or coincident with $\overline{CE}$ transition LOW and CE_2 transition HIGH.

Switching Waveforms

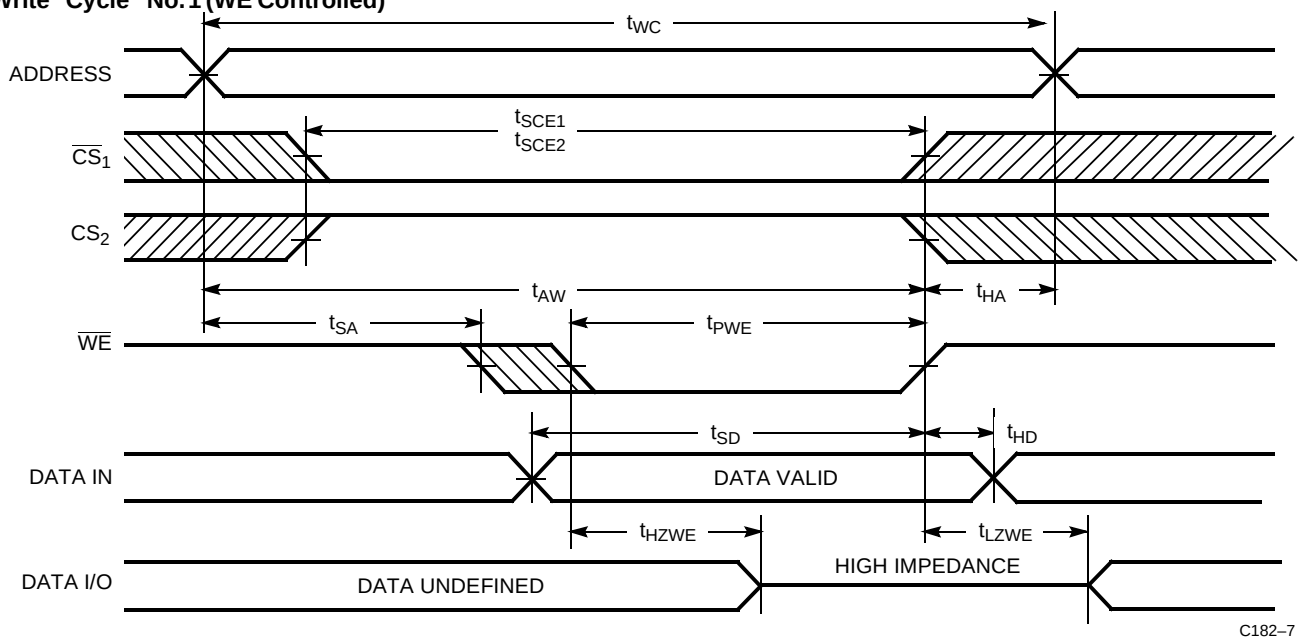
Read Cycle No. 1 [4, 9]



Read Cycle No. 2 [4, 10]



Write Cycle No. 1 ($\overline{WE}$ Controlled) [6]

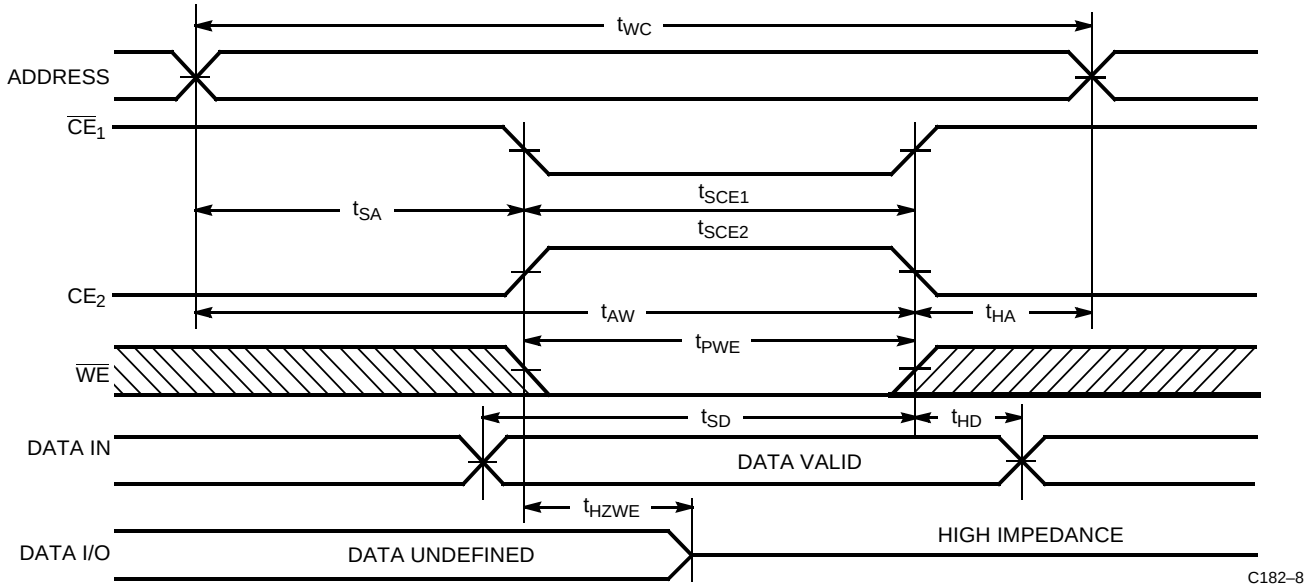


Notes:

9. Device is continuously selected. $\overline{OE}$, $\overline{CE}_1$ = V_{IL}. CE_2 = V_{IH}.
10. If $\overline{CE}_1$ goes HIGH and CE_2 goes LOW simultaneously with $\overline{WE}$ HIGH, the output remains in a high-impedance state.

Switching Waveforms (continued)

Write Cycle No. 2 ($\overline{CE}$ Controlled) [6, 10]



Truth Table

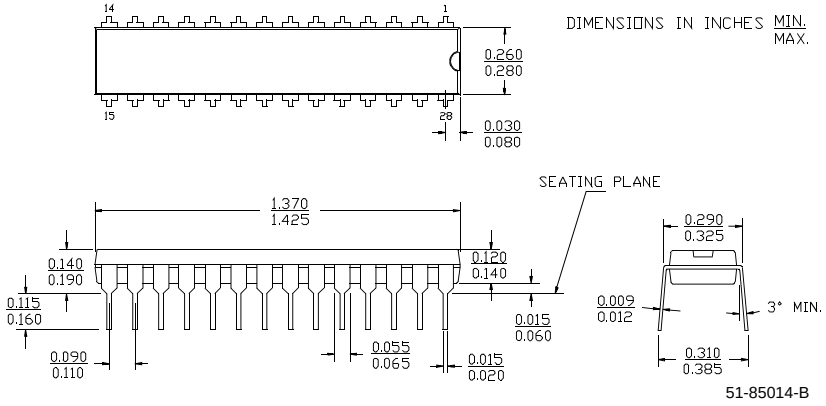
$\overline{CE_1}$	CE_2	OE	WE	Data In	Data Out	Mode
H	X	X	X	Z	Z	Deselect/Power-Down
L	H	L	H	Z	Valid	Read
L	H	X	L	Valid	Z	Write
L	H	H	H	Z	Z	Output Disable
X	L	X	X	Z	Z	Deselect

Ordering Information

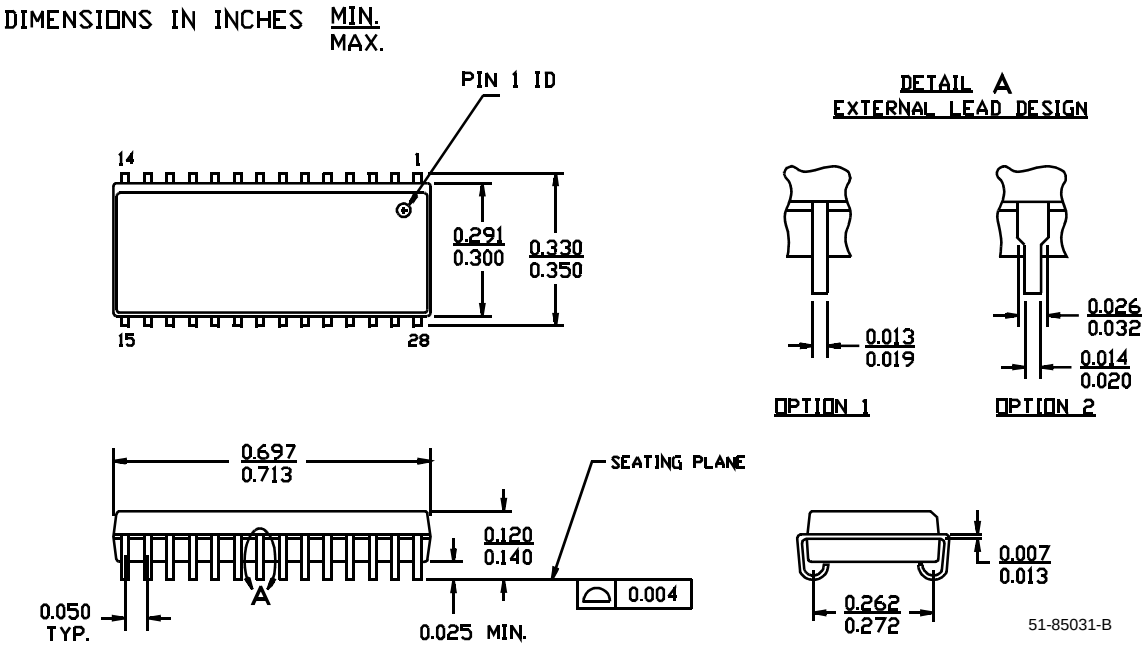
Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
25	CY7C182–25PC	P21	28-Lead (300-Mil) Molded DIP	Commercial
	CY7C182–25VC	V21	28-Lead Molded SOJ	
35	CY7C182–35PC	P21	28-Lead (300-Mil) Molded DIP	Commercial
	CY7C182–35VC	V21	28-Lead Molded SOJ	
45	CY7C182–45PC	P21	28-Lead (300-Mil) Molded DIP	Commercial
	CY7C182–45VC	V21	28-Lead Molded SOJ	

Package Diagrams

28-Lead (300-Mil) Molded DIP P21



28-Lead (300-Mil) Molded SOJ V21



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REV.	**ECN NO.**	**Issue Date**	**Orig. of Change**	**Description of Change**
**	106825	09/15/01	SZV	Change from Spec number: 38-00110 to 38-05031